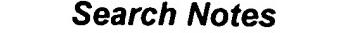


<b>Search Notes</b> 	<b>Application/Control No.</b>	<b>Applicant(s)/Patent under Reexamination</b>
	10/701,321	KIM, JOUNG-YEAL
	<b>Examiner</b> Anh Q. Tran	<b>Art Unit</b> 2819

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
East search-see printout		11/30/2005	AT